



Field Emission Model for PIC-DSMC Simulations Based on Nanoscale Surface Characterization

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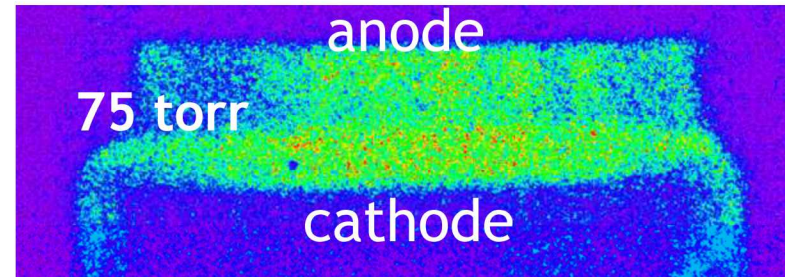
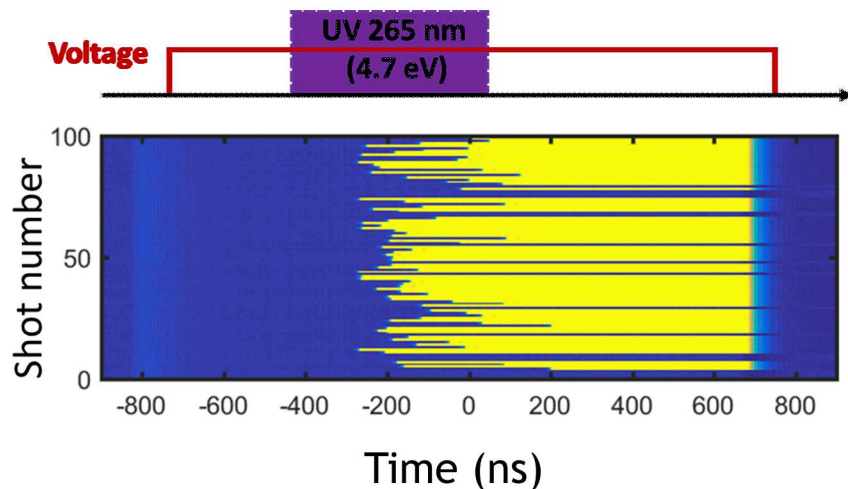
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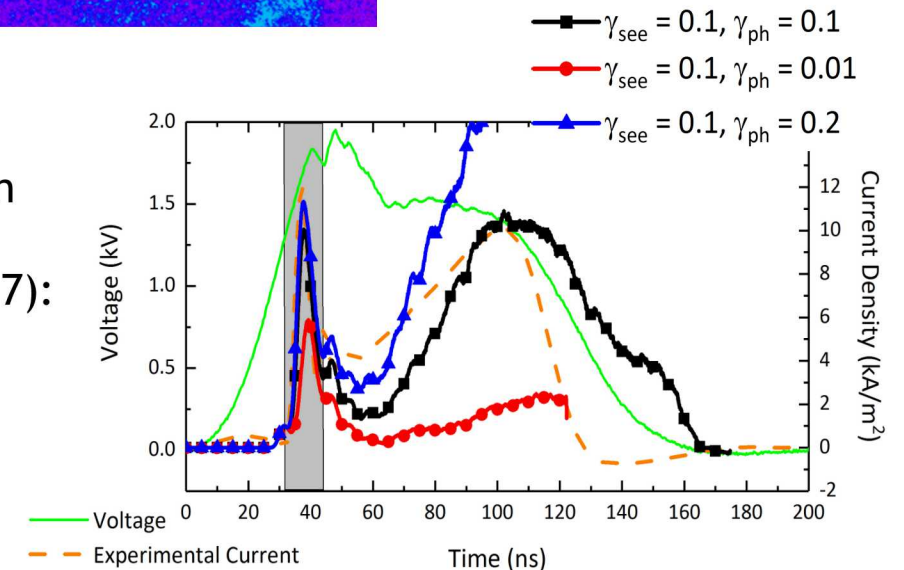
Introduction/Motivation

- We are interested in modeling a variety of discharge situations: from streamers at atmospheric pressure to vacuum arcs
- We have multiple projects focused on how interactions with surfaces drive discharge
 - AMPPED is investigating photoemission and ion-induced SEE from surfaces:

Photon-assisted breakdown (E. Barnat, MeVArc 2018)



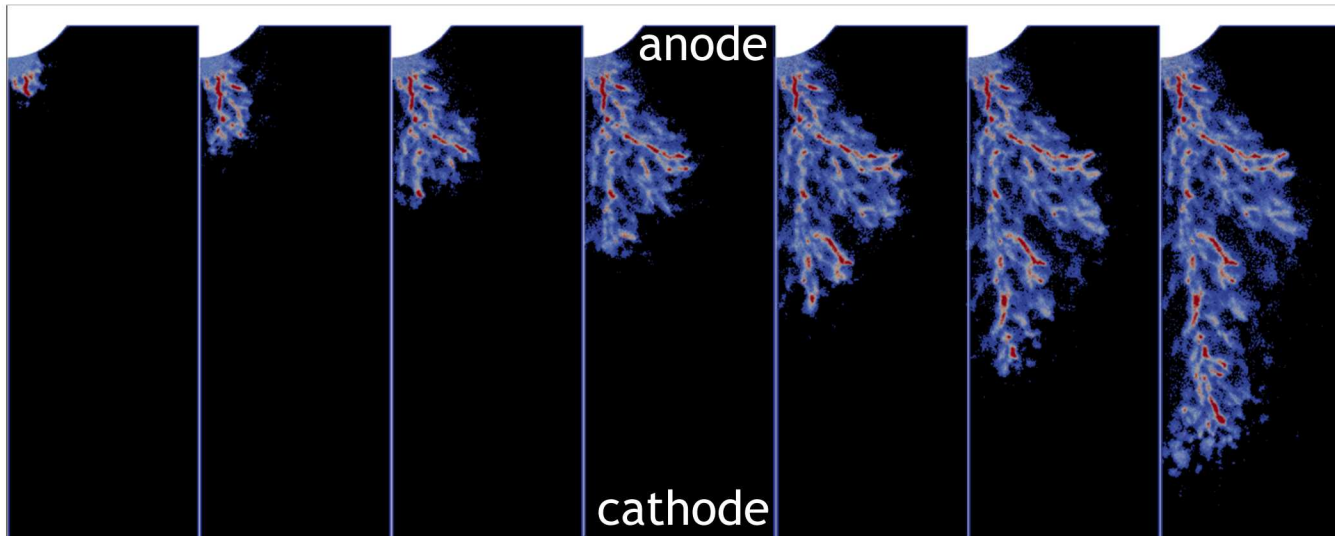
Dependence of low-pressure discharge on surface properties (A. Fierro, ICNSP 2017):



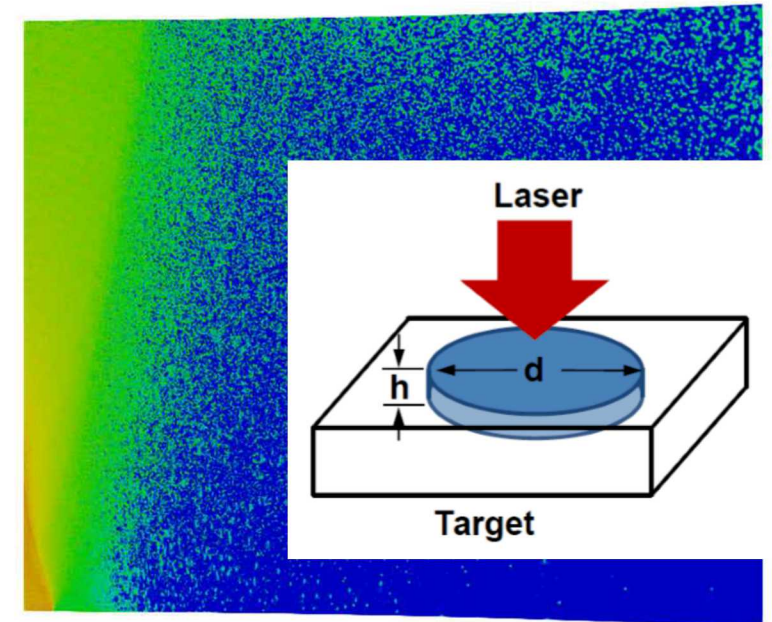
Introduction/Motivation

- We desire predictive PIC-DSMC breakdown simulations
 - Here predictive means capturing the bounds of discharge behavior due to stochastic variation of real surfaces (variation of contaminants, grain boundaries, dislocations, etc.) as built
 - It also means that we must perform rigorous Verification and Validation efforts before a model is considered useful

3D Streamer evolution (A. Jindal, ICOPS 2019):

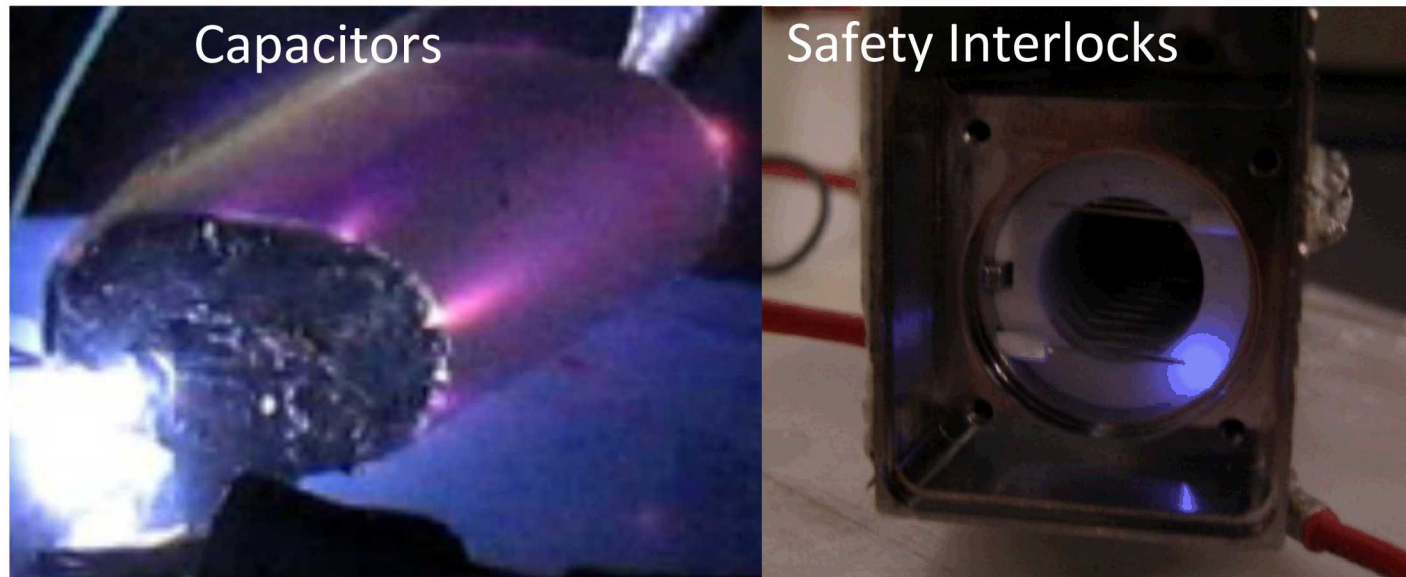


Laser-triggered switch
(A. Fierro, MeVArc 2018):



Vacuum Arc Initiation Project

- Vacuum discharge is critical to many modern devices.
 - Critical failure mechanism → Want to avoid
 - Mode of operation → Want to have predictable behavior



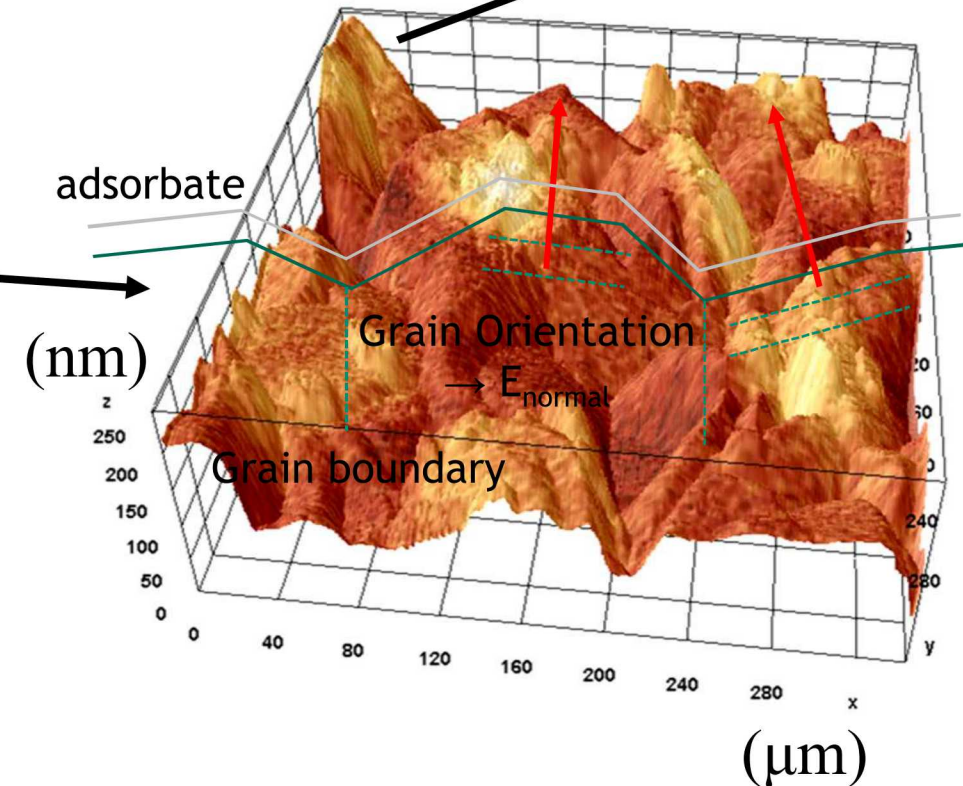
Vacuum Arc Initiation Project

- Vacuum discharge is critical to many modern devices.
 - Critical failure mechanism → Want to avoid
 - Mode of operation → Want to have predictable behavior
- We have a project to understand vacuum field emission from well-characterized surfaces to create physics-based models for use in large-scale PIC-DSMC breakdown simulations
 - Field emission is necessary precursor to a breakdown event. No field emission → no breakdown.
 - Employ Scanning Tunneling Microscopy and PhotoEmission Electron Microscopy to characterize surface very locally, and then apply high fields to initiate breakdown. Very locally = $\sim 0.1\text{-}10\text{ nm}$
 - Address the problem of not knowing the state prior to discharge at the location of discharge by characterizing and then discharging.
 - Apply known layers of dielectric (e.g., TiO_2 , MgO) to challenge models and begin investigation of role of surface contaminants.
 - Utilize a “meso-scale” ($0.1\text{-}1.0\text{ }\mu\text{m}$) model of the surface for PIC-DSMC simulation of breakdown

Why local characterization?

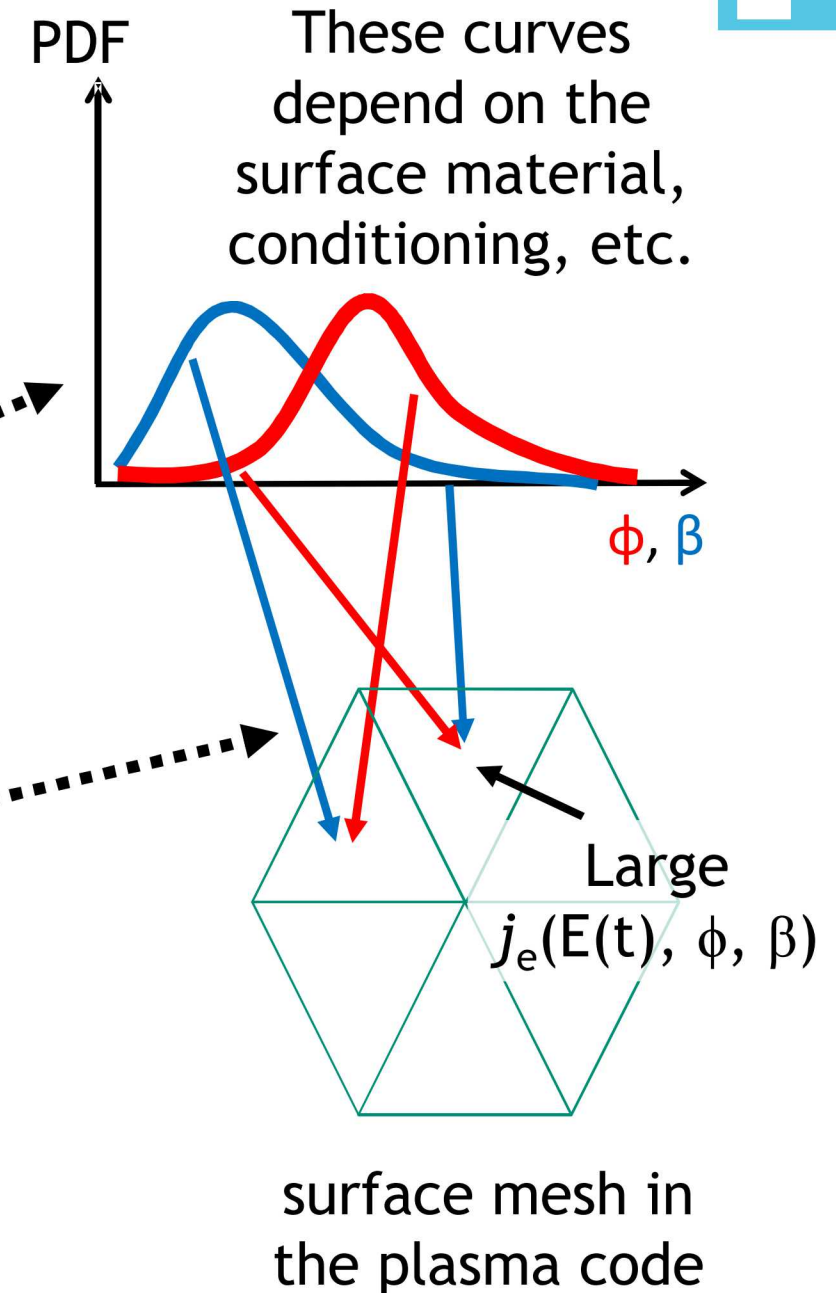
- Fowler-Nordheim field emission:
 - Typical use in macro-scale models is to curve-fit measured $j(E)$ from the as-built electrode
 - Can result in $\beta \sim 10\text{-}1000$!!!
- We want to locally characterize the surface to eliminate β as a fit parameter
 - Use Scanning Tunneling Microscopy (STM) and Atomic Force Microscopy (AFM) to measure topology (β)
 - Use PhotoEmission Electron Microscopy (PEEM) to measure work function (ϕ)
 - Use measured distributions for ϕ and β to inform macro-scale model for discharge simulations

$$i = A_{eff} A_{FN} \frac{(\beta E)^2}{\phi t^2(y)} \exp \left[- \frac{B_{FN} v(y) \phi^{3/2}}{\beta E} \right]$$



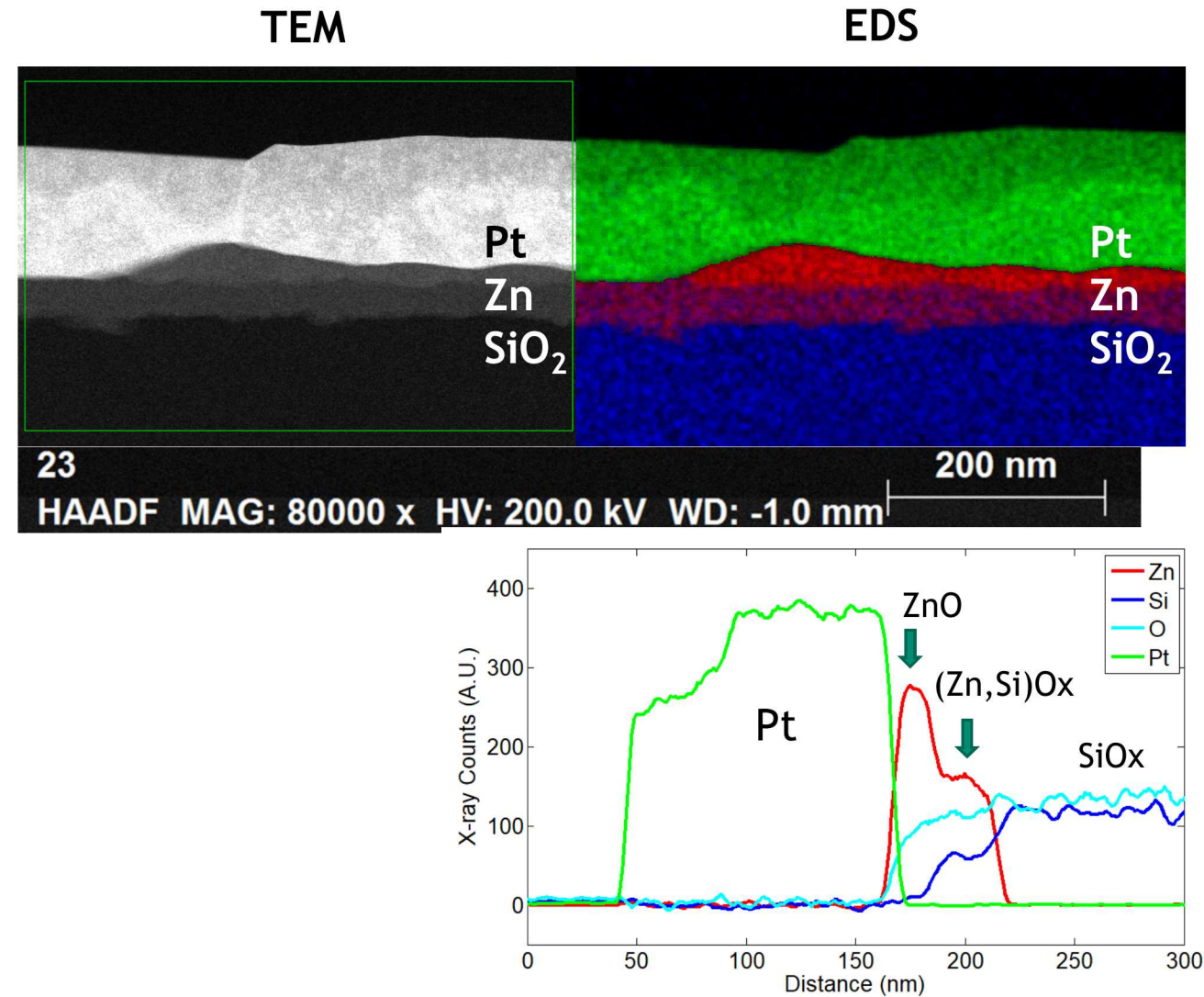
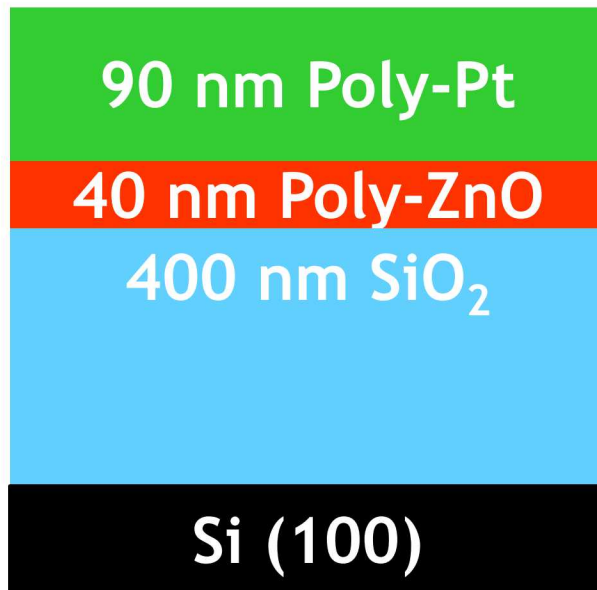
Overview

- Create Pt electrode via sputter deposition
- Controllably contaminate Pt via Atomic Layer Deposition
- Measure work function, local topology, and electron emission for sample
- Generate probability density functions (PDF) for local work functions and effective topological field enhancement
- Incorporate measured *atomic-scale* distributions into discharge simulations by populating time-varying *meso-scale* element-based data from the PDFs
- Compare family of plasma discharge simulations to measured breakdown behavior

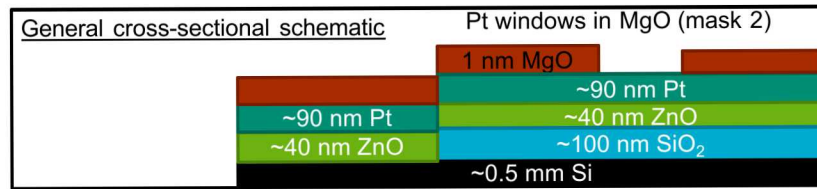


Characterization of the Electrode Stack

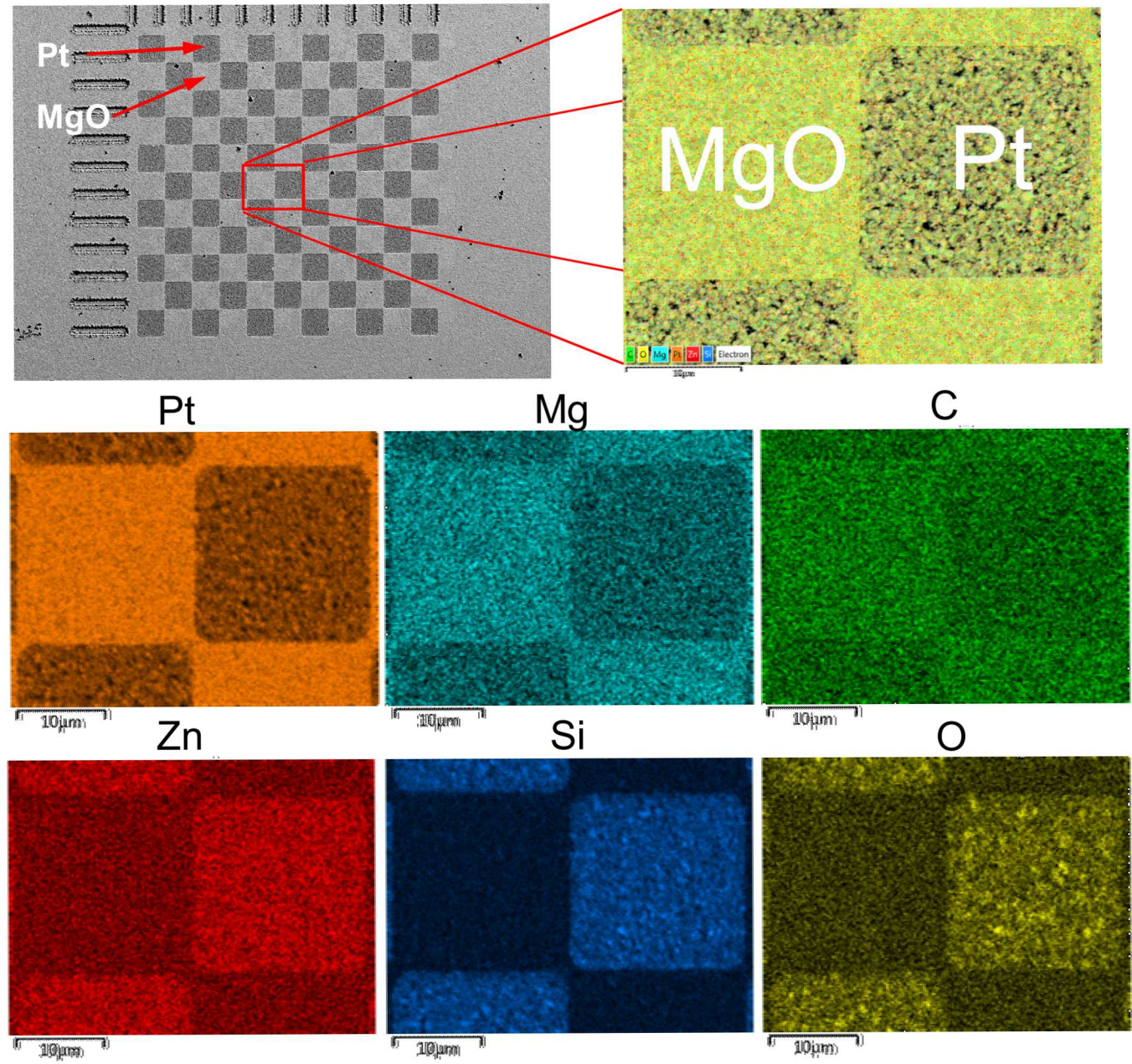
- Polycrystalline platinum electrode
 - Thermal SiO₂-Si (100) substrate
 - RF sputtered Pt metal thin film & ZnO adhesion layer
 - Ambient anneal- 1 hr. at 900°C



Characterization of the Electrode Stack

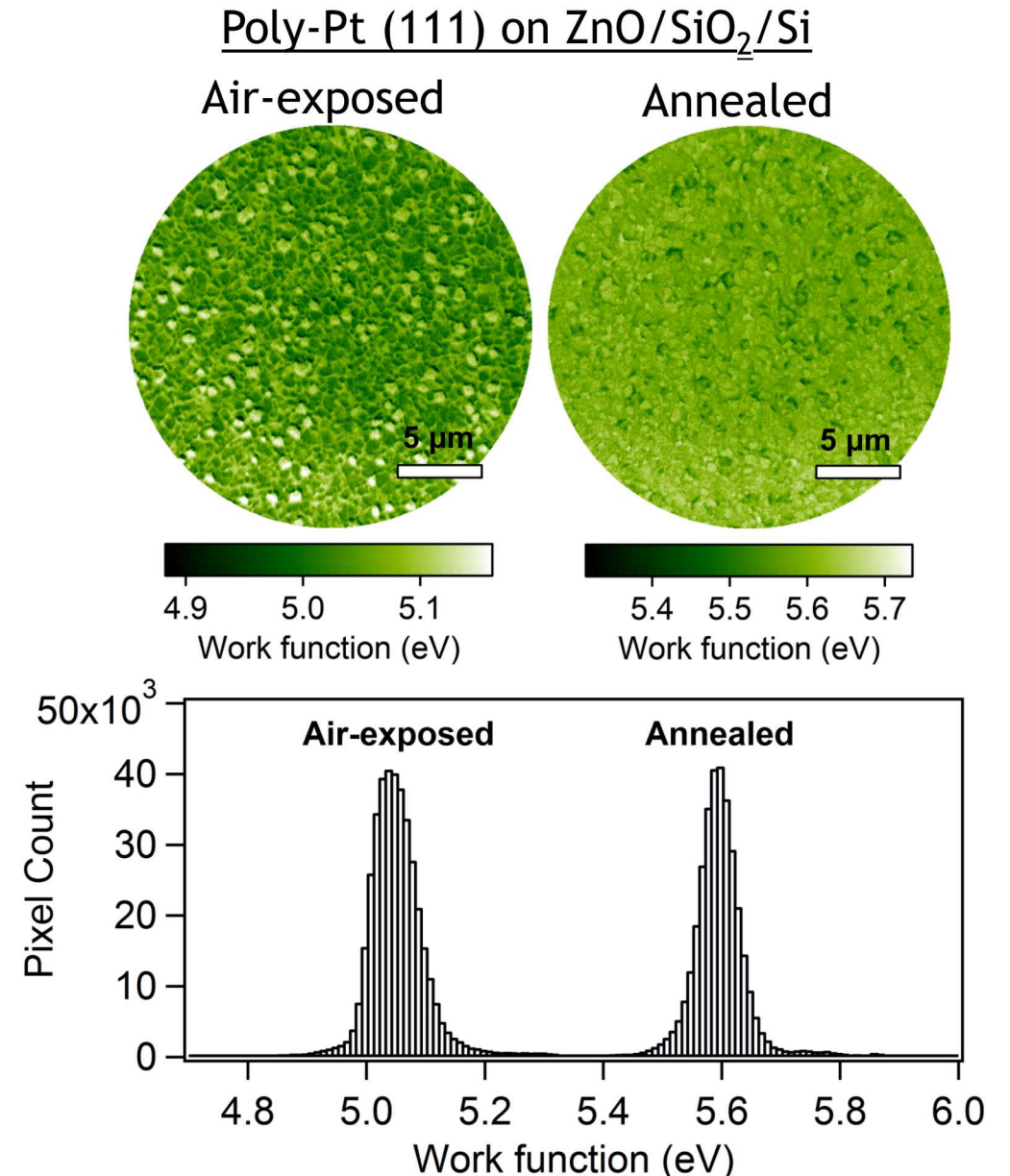


- To investigate surface contamination, put down a 1nm layer of MgO
 - Made “checkerboard” pattern via etch for direct comparison of Pt versus MgO/Pt emission and breakdown
- Use Scanning Electron Microscopy (SEM) and Energy Dispersive X-Ray Spectroscopy (EDS) to verify surface composition
 - Etch apparently went completely through the Pt, but also left patchy MgO
 - C contamination



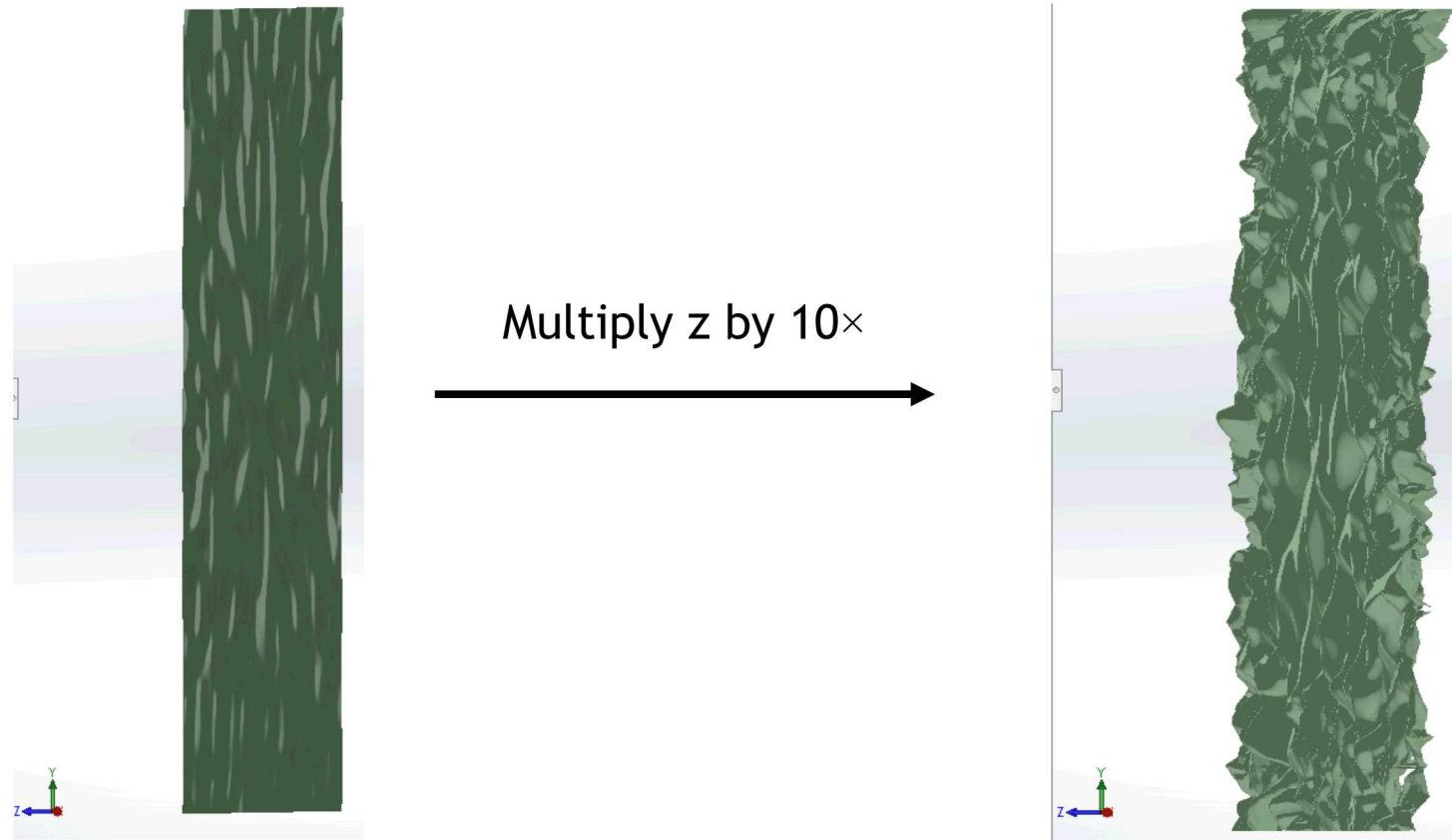
PEEM Measurement of Work Function Variation

- Measured spatial variation of local work function using PhotoEmission Electron Microscopy
 - Variation across given Pt surface relatively small – only a few percent
 - However, ϕ is in the exponential and the tail of the distribution can initiate field emission and eventually breakdown
- Significant ($\sim 10\%$) decrease in the work function due to surface contaminants picked up via exposure to air
- Use the $\sim 10\text{nm}$ -scale PDF's in meso-scale model to set element work functions in PIC-DSMC simulations



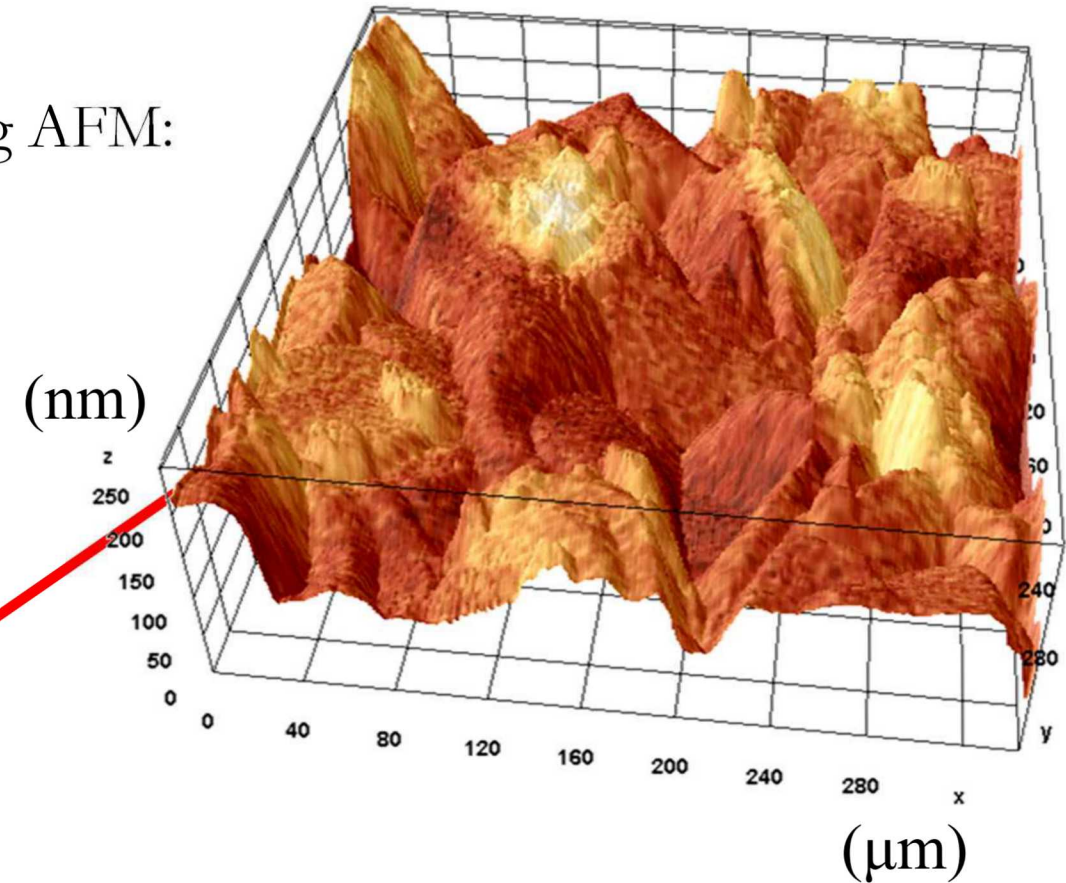
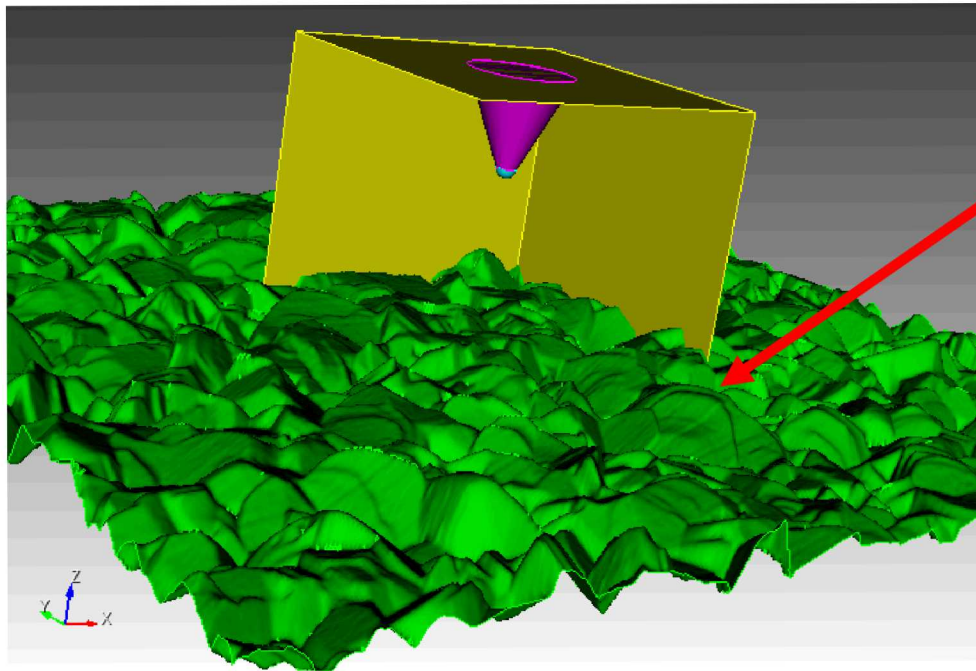
AFM Surface Characterization

- Actual surface has virtually no significant topology and thus $\beta \sim 1$ everywhere.
- To demonstrate spatial variation of field emission across the surface we show results here based on multiplying the surface relief by $10\times$



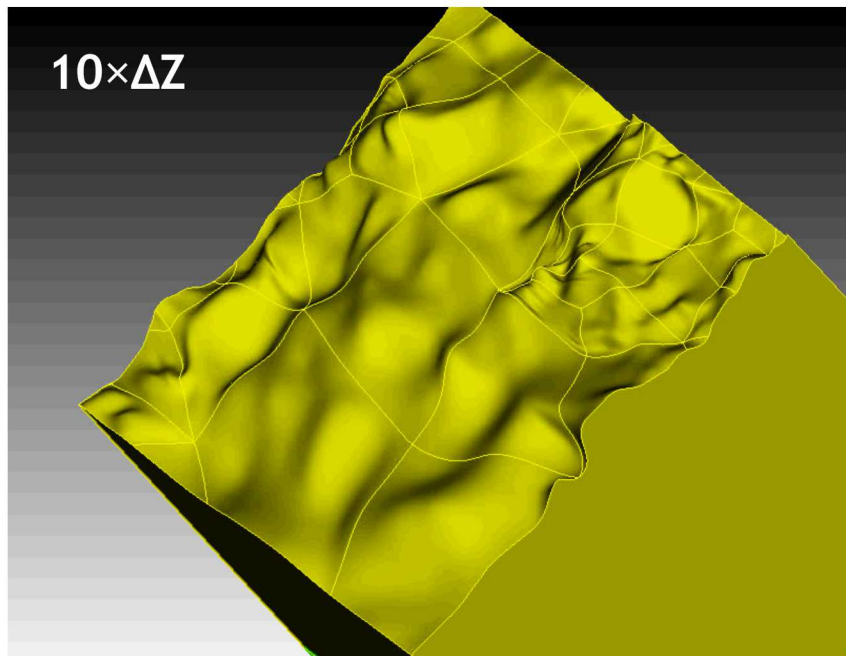
AFM topology \rightarrow topological atomic-scale β

- Measure surface topology before breakdown using AFM:
- Load topology into Cubit and mesh the surface in order to use electrostatic solver
 - Place flat anode $\sim 10\mu\text{m}$ from as-measured cathode
 - Use ~ 1 nm elements near cathode to resolve features

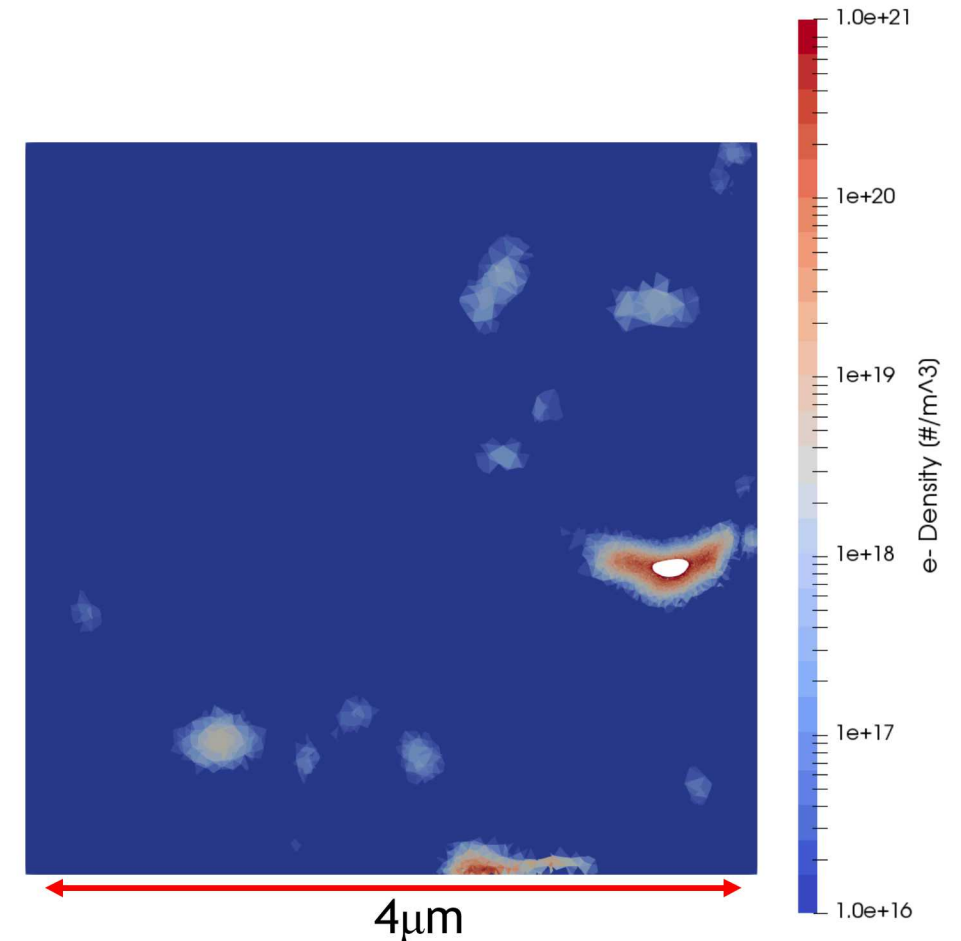


Simulation of Emission from AFM Surface

- With the resolved ($\Delta x < 10\text{nm}$) mesh, simulate the emission from the AFM surface
 - Show contours of e^- density just above the cathode surface
 - Some clipping of the topology is seen for the largest feature
- See several large-scale features that emit, otherwise very little emission

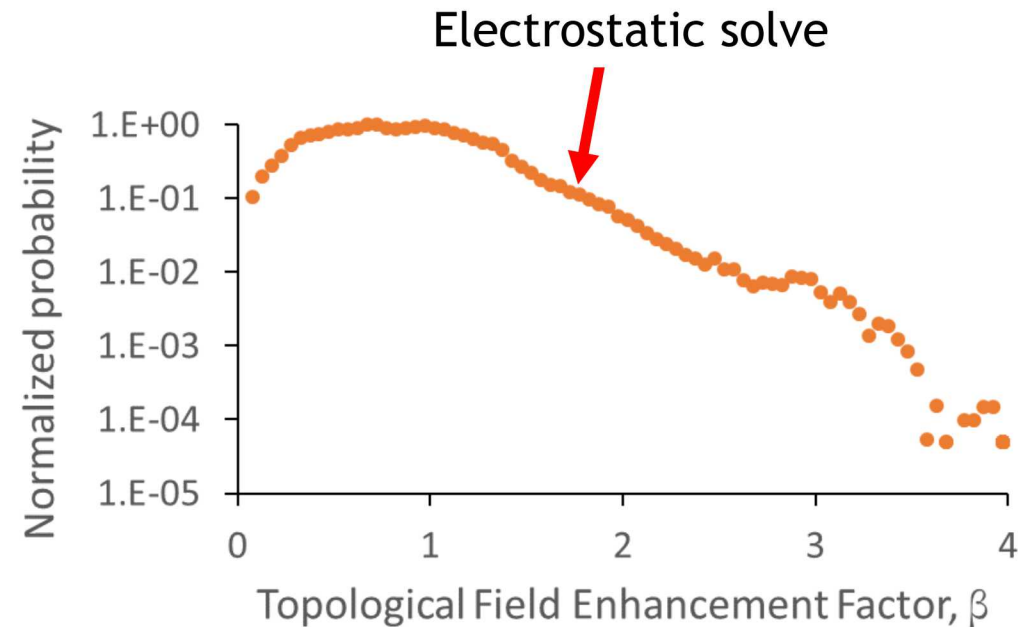
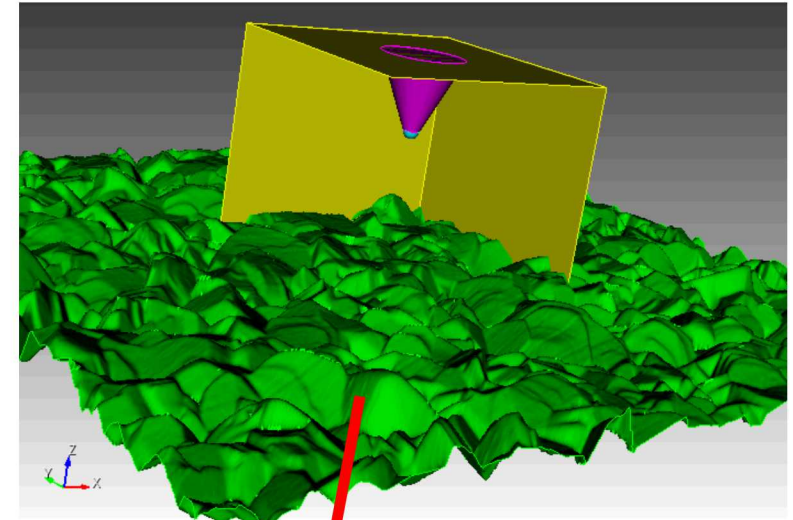


Simulate emission
in PIC-code



AFM topology \rightarrow topological atomic-scale β

- Compute E_{norm} and A_{proj} for every element face in the resolved STM mesh
 - $<10\text{nm}$ elements; $\sim 600\text{K}$ surface faces
- Get projection factor, $f_{\text{proj}} = \frac{\sum_{\text{faces}} A_{\text{face}}}{\sum_{\text{faces}} A_{\text{proj,face}}}$
 - For present data $f_{\text{proj}} \sim 1.15$
- Create $\sim 10\text{nm}$ scale PDF of $\beta = \frac{E_{\text{norm}}}{E_{\text{applied}}}$
- Some elements will have $\beta < 1$
 - Globally the surface could be tilted
 - Sides of “sharp” atomic features



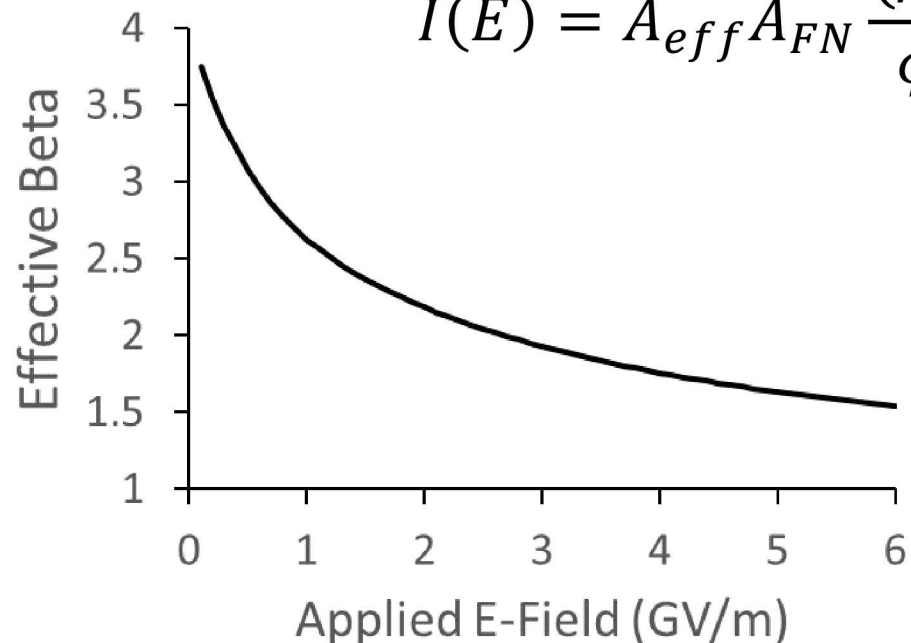
Meso-scale Model for Surface Variations

- We have measured atomic-scale (1-10nm) PDF's of the work function and topological field enhancement factor
- Must convert these to the meso-scale (0.1-10 μm). Some options:
 1. Just pick the meso-scale β and ϕ from the atomic-scale PDFs
 2. Make an effective β and ϕ to use at the meso-scale
 3. “Brute force” – for each meso-scale element face, pick N local emitters (unique β 's and ϕ 's)
- The first option obviously has artificially large variation for different surface realizations in simulations. We will not consider it further.
 - Sometimes get an extreme tail value and then field emit based on the meso-scale element's area
 - Other times there will be no tail values picked and no field emission until much higher fields

Meso-scale Model for Surface Variations

- Can we make an effective β (and ϕ) from the data and/or atomic-scale β PDFs?
- Measure/compute the total field emission current versus E_{applied}
- Non-linear solve for β_{eff} :

$$I(E) = A_{\text{eff}} A_{FN} \frac{(\beta_{\text{eff}} E)^2}{\phi t^2(y)} \exp \left[-\frac{B_{FN} v(y) \phi^{3/2}}{\beta_{\text{eff}} E} \right]$$



→ β_{eff} depends on E_{applied} !

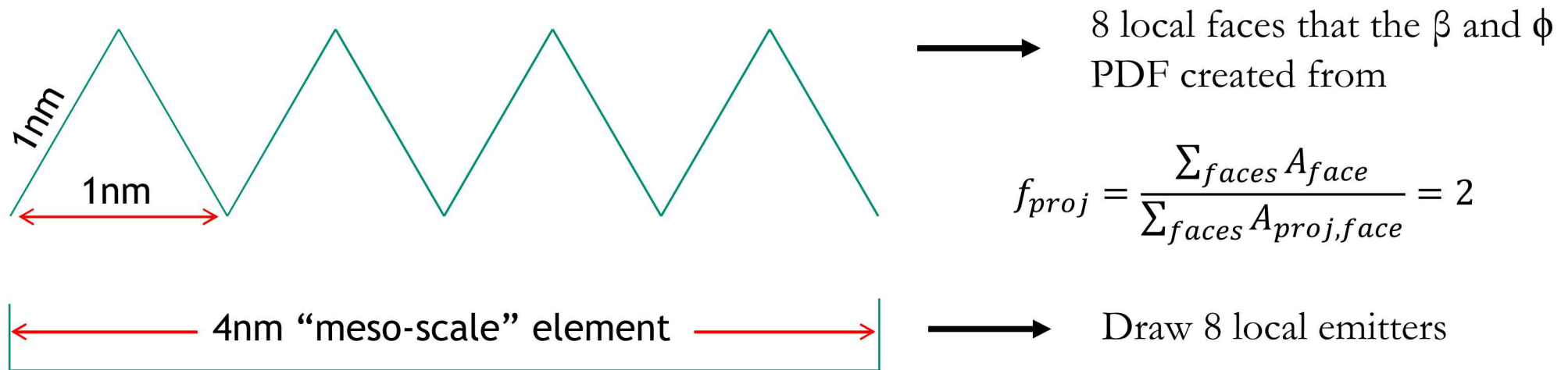
- This makes sense: small β regions “turn on” at higher fields and pulls the effective β lower
- The precise functional form depends on the atomic-scale β PDF

Meso-scale Model for Surface Variations

- We are left with “brute force” -- for each meso-scale element face, pick N local emitters (randomly pick unique β 's and ϕ 's) from the atomic-scale measured distributions:

$$N = \frac{A_{element}}{A_{resolved}} f_{proj}$$

- Must scale the number of local emitters to draw:



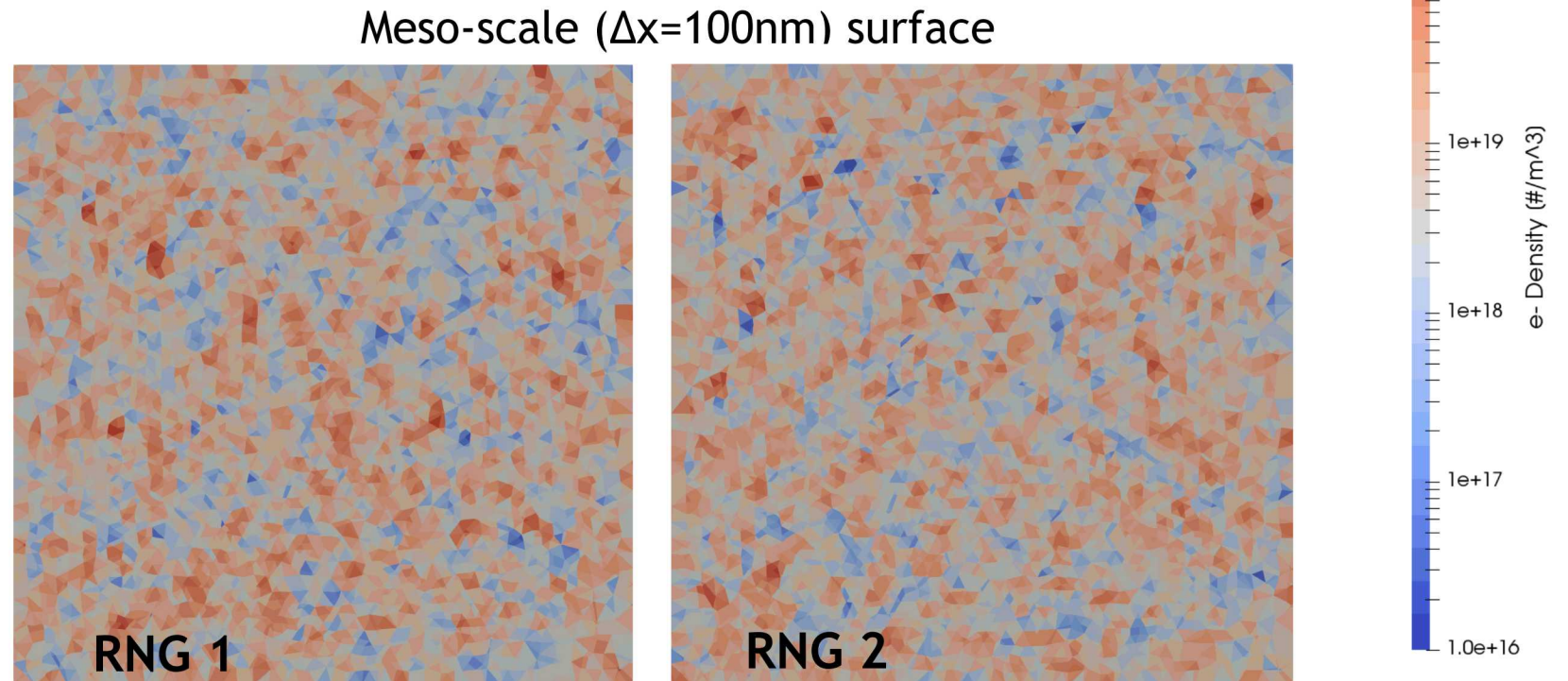
Meso-scale Model for Surface Variations

- However, we don't have to store all N local emitters for each surface element face
 - Field emission is highly non-linear and the majority of emitters (β and ϕ) can be neglected
- Store every atomic-scale emitter (β and ϕ) that appreciably contributes to the current
 - A threshold current contribution of 0.1% results in storing $\sim 0.01\%$ of the atomic-scale emitters
 - $1 \mu\text{m}^2$ element has 10^4 – 10^6 atomic-scale emitters \rightarrow store < 1000 emitters.
- PIC field emission algorithm each Δt :
 - Compute E_{norm} on each surface element face
 - Loop over all ~ 100 atomic-scale emitters:

$$I_{\text{face}} = \sum_{\text{emitters}} A_e A_{FN} \frac{(\beta_e E_{\text{norm}})^2}{\phi_e t^2(y)} \exp \left[- \frac{B_{FN} v(y) \phi_e^{1.5}}{\beta_e E_{\text{norm}}} \right]$$

Meso-scale Field Emission Simulations

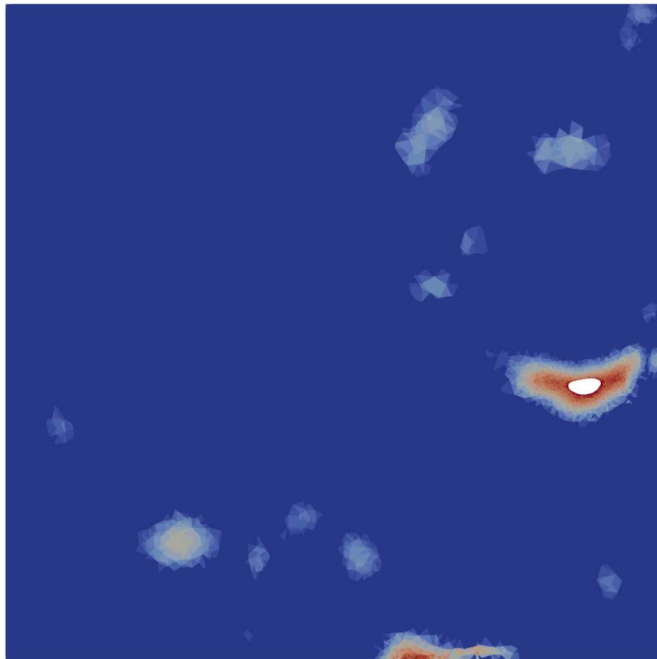
- Meso-scale model does show stochastic variation in the e- density just above the surface based on the random seed
- Goal is to be able to sample many possible surfaces (e.g. different β 's and ϕ 's) and compute breakdown probabilities for as-built surfaces



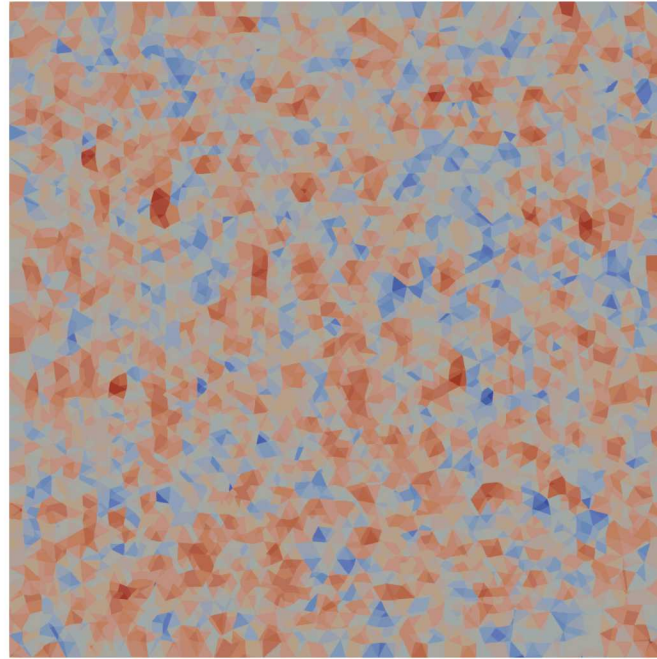
Meso-scale Field Emission Simulations

- Contours of electron density just above the cathode show very different spatial variation between the meshed STM surface and the flat, meso-scale surfaces
 - The STM surface was sputtered deposited Pt \rightarrow large, \sim micron-scale features are apparent
 - The current model picks atomic-scale emitter properties (β 's and ϕ 's) independently for every “meso-scale” surface elements. Clearly not independent for sputtered deposited Pt

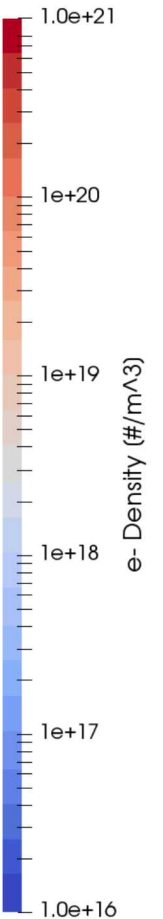
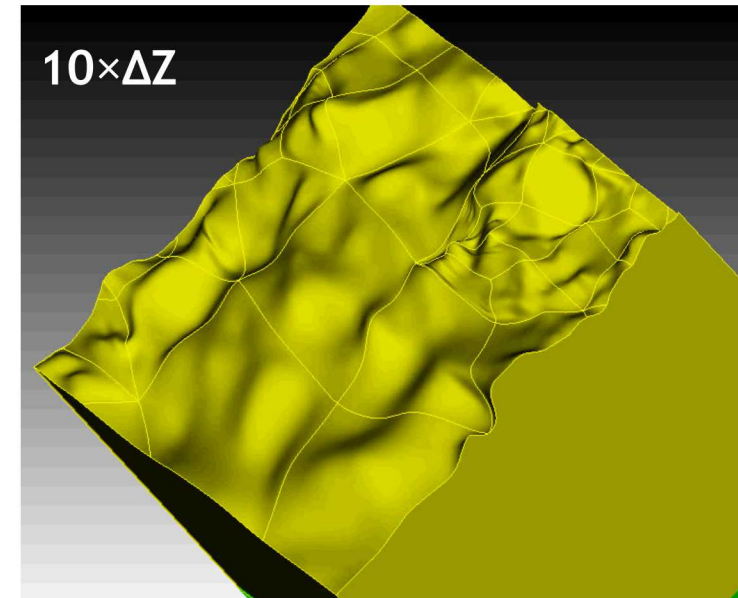
STM ($\Delta x < 10\text{nm}$) surface



Meso-scale ($\Delta x = 100\text{nm}$) surface

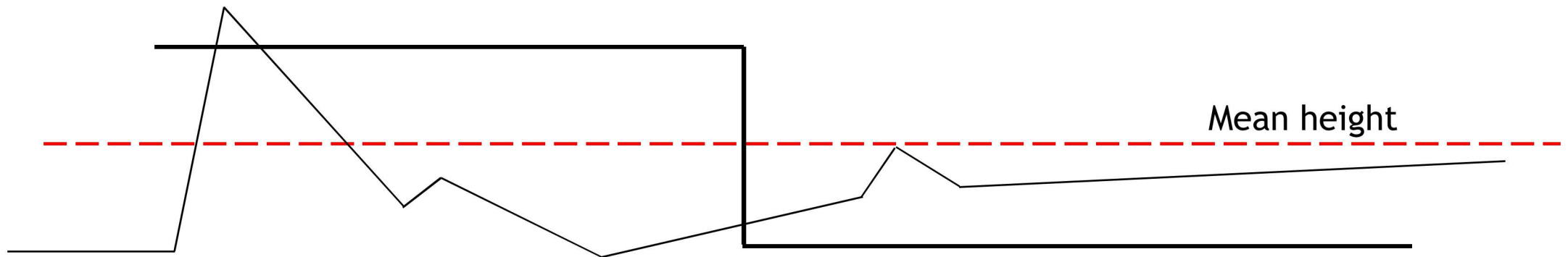
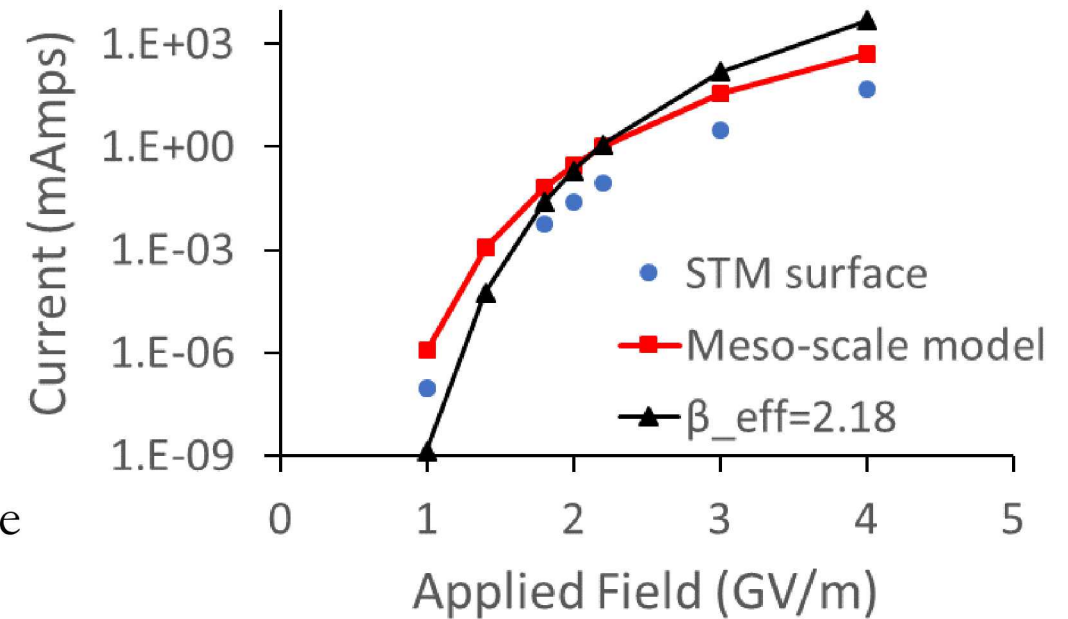


STM surface topology



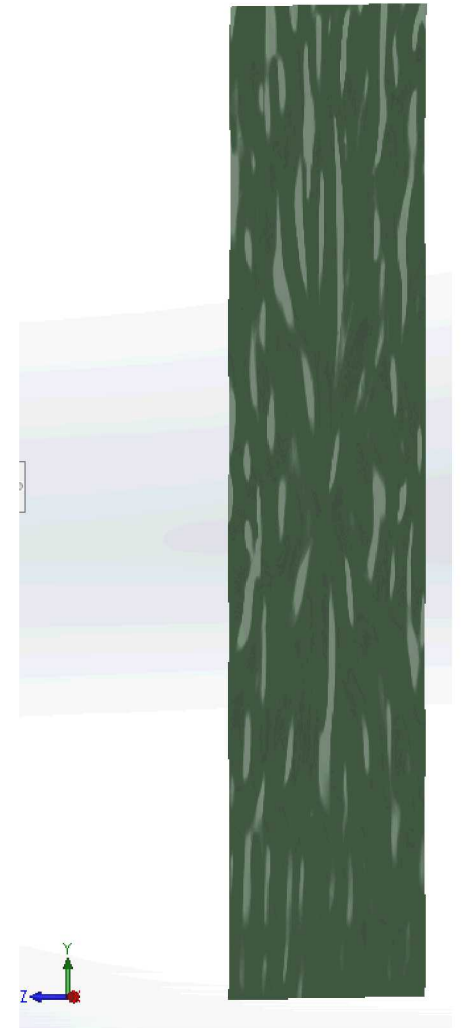
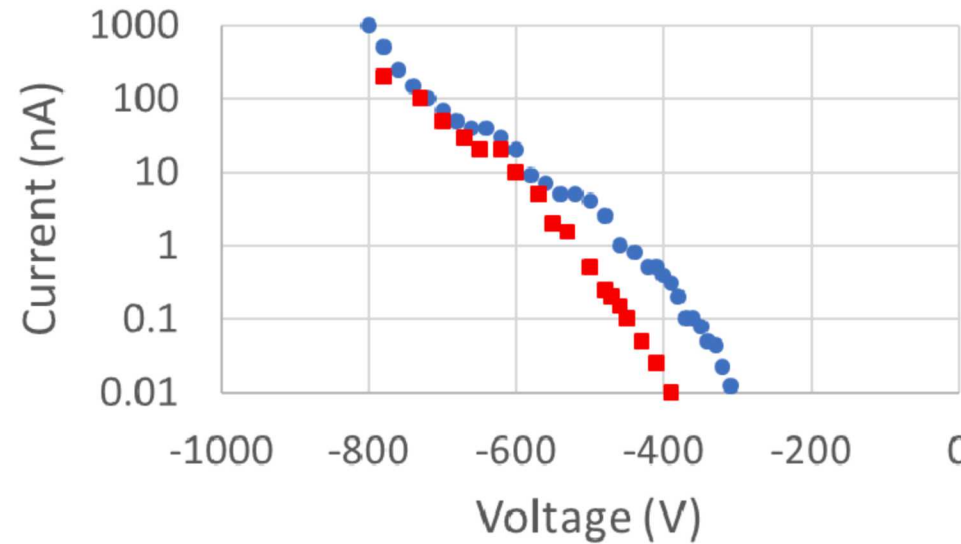
Meso-scale Field Emission Simulations

- Compare computed global current versus applied field for the resolved STM surface and meso-scale model surface
 - Stochastic variation in the meso-scale currents small
- The meso-scale model currents have the same trend as the STM surface, but $\sim 12 \times i_{\text{STM}}$
 - Difference partially (mostly?) from variation in fields due to changes in gap distance for the STM surface
 - Flat anode placed $10.4\mu\text{m}$ from the mean STM cathode height



Initial Local STM Breakdown Results

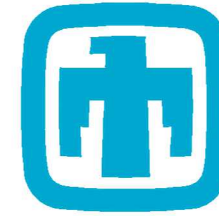
- Took local field emission i-V curves with tip radius $< 100\text{nm}$ at a distance of $\sim 200\text{nm}$
- Relatively feature-less surface with small- β within the region of the tip field footprint
- Breakdown at $\sim 4\text{ GV/m!}$
- This seems to be evidence that, at least for relatively smooth sputter deposited Pt, we do not have small- β atomic-scale features that grow into large- β features which then allow breakdown to occur at $\sim 10\text{ MV/m}$.
- Perhaps there is a special feature somewhere on a $\sim 1\text{ cm}^2$ electrode that results in (or can grow to) a large enough β to get breakdown at $\sim 10\text{ MV/m}$ that was not present on our $\sim 10^{-6}\text{ cm}^2$ sampled area.



$\Delta z < 0.1\text{ }\mu\text{m}$ over $10\text{ }\mu\text{m}$

Conclusions

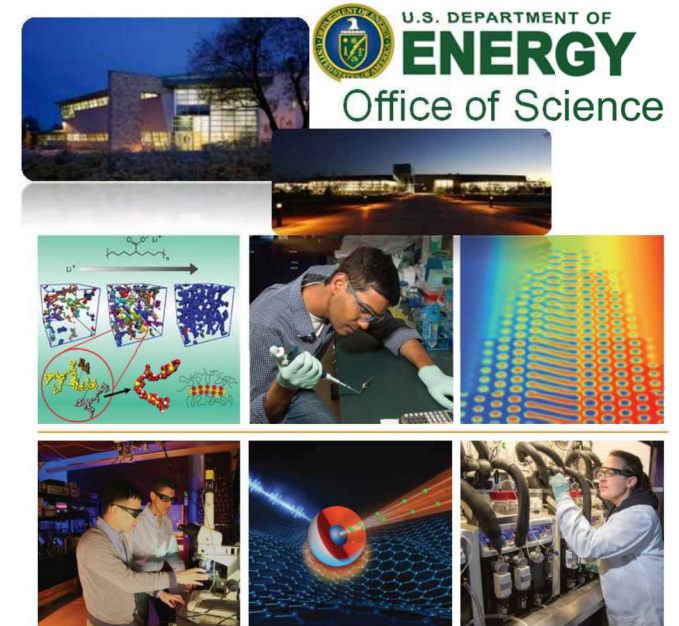
- Investigating surfaces at the atomic scale to characterize features relevant to vacuum field emission.
 - Want to clarify β -based field emission so β really is only geometry induced field enhancement.
- By examining field emission at the nanoscale, we have attempted to create a meso-scale physics-based model suitable for predictive (and stochastic) PIC simulation of emission
 - Still have a long way to go – any ideas/suggestions??
- Characterized region, then performed local discharge in STM (spatially constrained surface participation) → Breakdown occurred at ~ 4 GV/m!
 - Region was flat and uninteresting – the breakdown field is consistent with breakdown from region with a small β



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